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[UNITED KINGDOM]

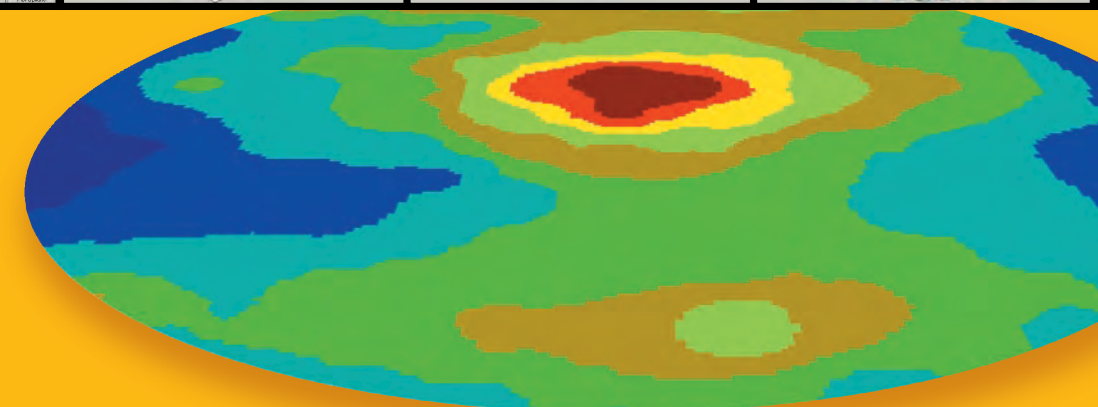
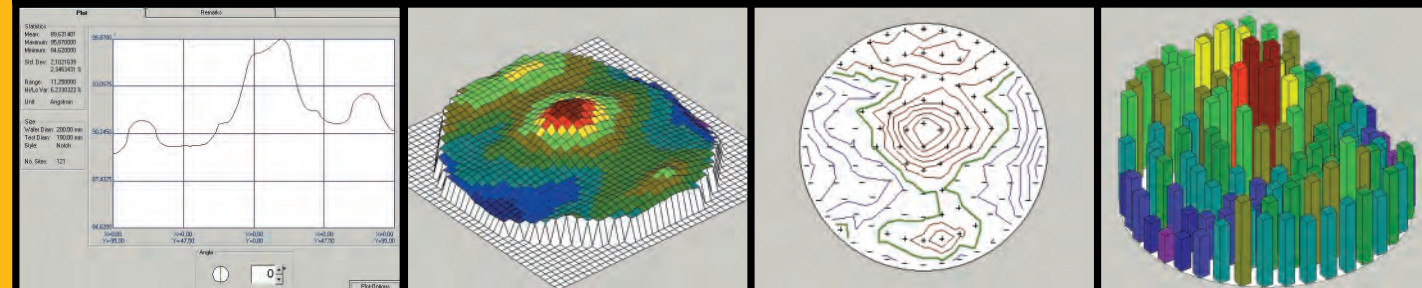
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[SUPPORTED IMPORT FORMATS]

ASCII
Four Dimensions
CDE ResMap
Filmetrics 3.0 and 4.0
Jenoptik TWIN
KLA-Tencor RS100
KLA-Tencor F5
Nanophotonics
Nicolet
OPUS
Plasmos

Prometrix RS
Prometrix UV
QC Solutions SCP 7000
Rudolph
Sentech
SOPRA SE
Thermawave Optiprobe
Thermawave Thermaprobe

Import of data from metrology tools that directly write the WAFERMAP format:

E+H
Foothill
SigmaTech
Jenoptik

Additional import formats can be implemented upon request.

ALL OTHER COUNTRIES:

BOIN scientific software

Boin GmbH
Haldenweg 25
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SYSTEM REQUIREMENTS

- Microsoft Windows 95, 2000 or XP Prof.
- PC fulfilling Microsoft minimum requirements for the specific Windows OS
- VGA (min. 640 x 480)
- 12 MB hard disk space

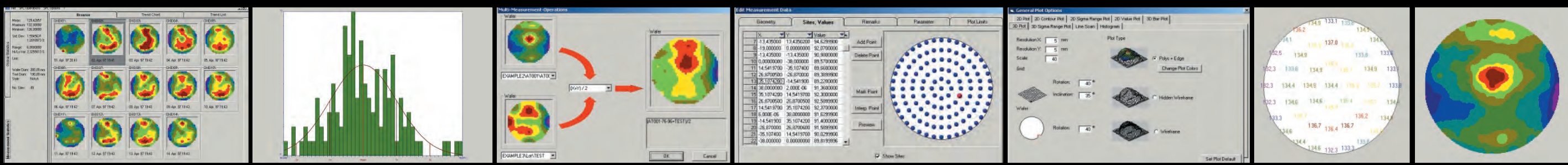
The WAFERMAP Evaluation version is available at no obligation for a 30 day trial period. You can download it from <http://www.boin-gmbh.com>.

A CD-ROM Evaluation version is also available.

In developing a product that is truly making a difference in semiconductor manufacturing, Boin GmbH received the prestigious Editors Choice Best Product Award 1999, presented annually by Semiconductor International magazine, for its metrology software WAFERMAP. Semiconductor International announced 20 winners whose products are making a difference in semiconductor manufacturing.



WAFERMAP Software WAFERMAP Software



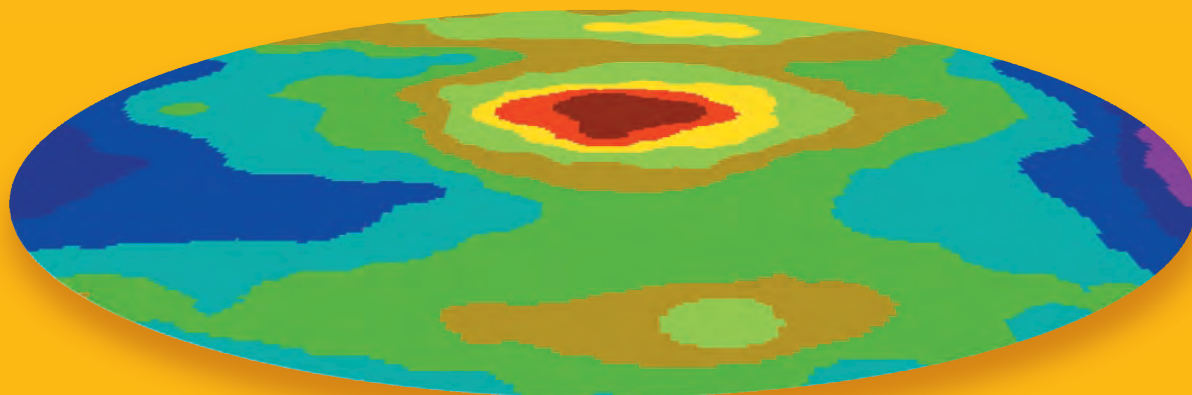
WAFERMAP is an award winning software package used to collect, edit, analyze and visualize measured physical parameters on semiconductor wafers.

WAFERMAP can import data files from various metrology tools such as ellipsometers, thickness gauges and four point probes. The imported data can then be visualized or printed as line scans, contour plots, 2D or 3D plots or as a histogram.

Several kinds of operations can be applied to the wafer maps such as rotation, shifting of the grid in the X or Y direction, or mirroring the data along the X or Y axis. Global operations such as adding or subtracting a constant or taking the 1st or 2nd derivative can be carried out. A Sigma Filter allows for the elimination of sites that exceed a user-defined range (e.g. measurement errors). In case of missing or invalid sites, a transformation to a standard circular or Cartesian grid can be performed. Different grids can be merged into a single new one. It is also possible to compare different sets of data by adding, subtracting or dividing entire wafer maps. Maps can be exported to ASCII data files.

Typical applications include map generation for manually operated metrology tools and standardized visualization for different automatic metrology equipment (e.g. different types of four point probes in the same fab).

WAFERMAP allows users to work off-line and to analyze and edit metrology data outside of the clean room. It is the perfect solution for paperless fabs.



[FEATURES]

+General

- Advanced xml-based Boim multi-column multi-wafer file format **[NEW]**
- Loading of multiple columns and wafers at once **[NEW]**
- Configurable 1D- (line scan), 2D- (contour or colored), 3D- (solid or wire frame), 3D bar chart-, value-, and sigma range plots
- Multicolor contour plot **[NEW]**
- Statistical analysis (histogram, calculation of mean, standard deviation, max, min, etc.)
- Import functions for data from different metrology tools (see page 1)
- Import of data from metrology tools that directly write the WAFERMAP file format (see page 1)
- Other import functions (e.g. ASCII files, OPUS)
- Export of *.jpg and *.bmp files **[NEW]**
- Export into *.html file format **[NEW]**
- Definition of any site pattern using a graphic editor
- Automatic generation of circular or Cartesian site patterns for any test diameter
- Extensive on-line help and HTML based user manual

+SPC

- Trend charts
- Trend lists
- X-Y-plots of statistical values **[NEW]**
- Global statistics ("All points, all wafers")
- Browser
- Trend charts and lists can be sorted by any criterion (date & time, mean, max, min, std. dev. etc.)
- Stacked maps
- Operations with files **[NEW]**

+Operations

- Global operations (add, subtract, divide, square, square root, etc.)
- 1st and 2nd derivative of a map
- File compare operations (add, multiply, ratio, average, etc.)
- File operations are applicable to files with different site distributions
- Shift (X and Y direction) and rotation of grids
- Mirroring of maps along the X and Y axis
- Averaging of radial zones
- Multiple files can be open simultaneously
- Multiple views of a single file can be selected and displayed simultaneously
- Multiple views can be printed on a single sheet, printouts are configurable

+Communication/Linking

- Inter-application communication via DCOM (ActiveX server)

[LICENSES]

+WAFERMAP for Windows Stand Alone licenses

WAFERMAP for Windows EDUCATIONAL: includes all graphics

WAFERMAP for Windows ADVANCED: includes all graphics, "Compare", "Operations", and "SPC"

WAFERMAP for Windows PROFESSIONAL: includes all graphics, "Compare", "Operations", "SPC", "Import", and "Export"

+WAFERMAP for Windows other licenses

WAFERMAP for Windows PROFESSIONAL Network License:

WAFERMAP for Windows PROFESSIONAL Site License

WAFERMAP for Windows OEM Solutions

